


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565949	<b>Applicant(s)/Patent Under Reexamination</b>  WEISS ET AL.
	<b>Examiner</b>  Hai H Huynh	<b>Art Unit</b>  3747

SEARCHED			
Class	Subclass	Date	Examiner
123	295	3-27-07	HHH
123	299	3-27-07	HHH
123	305	3-27-07	HHH
123	443	3-27-07	HHH
123	325	3-27-07	HHH
123	332	3-27-07	HHH
123	406.23	3-27-07	HHH
123	406.47	3-27-07	HHH
update	search	9-10-07	HHH
123	481	2-27-08	HHH
123	493	2-27-08	HHH
123	329	2-27-08	HHH
123	198DB	2-27-08	HHH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	3-27-07	HHH
	9-10-07	HHH
	2-27-08	HHH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
above	search	2-27-08	HHH